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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.	:	Unassigned	Confirmation No.	Unassigned
First Inventor	:	AZIMANE, Mohamed		
Filed	:	Concurrently		
TC/A.U.	:	Unassigned		
Examiner	:	Unassigned		
Docket No.	:	**US040161US2**		
Customer No.	:	24738		

Title: Method for Detecting Resistive-Open Defects In Semiconductor Memories

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

PRELIMINARY AMENDMENT

Sir:

Prior to calculation of the filing fee and examination please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims begin on page 3 of this paper.

Remarks/Arguments begin on page 7 of this paper.